

Notice of References Cited	Application/Control No. 10/812,444	Applicant(s)/Patent Under Reexamination MCCLESKEY ET AL.	
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	V	McVay, T. N., Bureau of Mines Report of Investigations 1960, No. 5620, 10 pages.
	W	Patten, L. E. et al, U.S. Geological Survey Professional Paper 1962, No. 450-C, 103-104.
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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